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US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S55 or S56	156	S57
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S48 and S55	2	S56
S35 or S37 or S38 or S39 or S40 or S41 or S42 or S43 or S44 or S45 or S46 or S47 or S49 c US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S35 or S37, or S38 or S39 or S40 or S41 or S42 or S43 or S44 or S45 or S	156	S55
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and ((mapping near2 data) with (addressable near2 memory))		S54
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and (translat\$3 with wrapper)	00	S53
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and ((address near2 decoder) with (memory near2 map))	_	S52
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and (shift\$3 near2 serially)	4	S51
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and (translat\$3 with (shift\$3 near2 serially))	-	S50
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and (translat\$3 with (shift near2 register))	œ	S49
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and ((component or element) with register)	83	S48
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and ((component or element) with (memory near2 map))	4	S47
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and (wrapper with (memory near2 map))	_	S46
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and ((component or element) near2 wrapper)	=	S45
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and ((second or another) near2 protocol)	14	S44
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and (protocol with translat\$3)	71	S43
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	S36 and ("boundary scan" with translat\$3)	2	S42

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US 20040260528 A Co-simulati WO 2003012640 A Behavior pu GB 2370134 A Digital circu				US 5943490 A Distributed US 5870588 A Design env		US 6026230 A Memory sir				US 6263303 B1 Simulator architecture				6377912 B1	6389379 B1	6421251 B1	US 6449284 B1 Methods at	6484280 B1	6493841 B1	US 6498999 B1 Method and		US 6567957 B1 Block base	US 6574778 B2 Block base		US 6629293 B2 Block base	6631470 B2		US 6686914 B2 Methods a
werriod of testing a data communication system Co-simulation system for interfacing high-level modeling system for electronic circuit design, I Behavior processor system for operating portion of user design and interfacing with host test Digital circuit co-simulation method for integrated circuit designing involves converting model:	Concurrent simulation of host system at instruction level and input/output system at logic leve Sequence of events detector for serial digital data which selectively outputs match signal in the Mothod of testing a data communication system.	Method for manufacturing test simulation in electronic circuit design	System and method for simulation of computer systems combining hardware and software int	Distributed logic analyzer for use in a hardware logic emulation system Design environment and a design method for hardware/software co-design	Emulation system with time-multiplexed interconnect	Memory simulation system and method Simulation/emulation system and method	Simulation server system and method	System and method for system level and circuit level modeling and design simulation using C	Method and apparatus for test generation during circuit design	Block based design methodology Simulator architecture	Timing-insensitive glitch-free logic system and method	Verification of message sequence charts	Method and apparatus for test generation during circuit design	Emulation system with time-multiplexed interconnect	Converification system and method	Array board interconnect system and method	iviernog for adaptive test generation via feedback from dynamic emulation. Methods and means for managing multimedia call flow.	Scan path test support	Method and apparatus for determining expected values during circuit design verification	Method and apparatus for design verification of an integrated circuit using a simulation test be	Method and apparatus for test generation during circuit design	Block based design methodology	Dynamic evaluation logic system and method	Methods and systems for automatically translating geometric data				
19840313 /14/38 20041223 20030213				19990824 703/28 19990209 703/13		20000215 703/13				20010731 716/1							20021119 /03/23		20021210 714/741		20030304 714/739							20040203 345/420